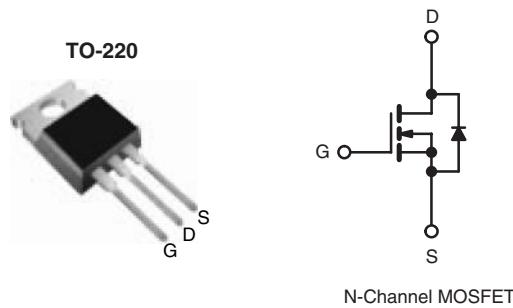


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	400
R _{D(on)} (Ω)	V _{GS} = 10 V 0.55
Q _g (Max.) (nC)	36
Q _{gs} (nC)	9.9
Q _{gd} (nC)	16
Configuration	Single



FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective C_{oss} Specified
- Lead (Pb)-free Available



RoHS*
COMPLIANT

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Single Transistor Flyback Xfmr. Reset
- Single Transistor Forward Xfmr. Reset (Both for US Line Input Only)

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRF740APbF SiHF740-A-E3
SnPb	IRF740A SiHF740A

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Gate-Source Voltage		V _{GS}	± 30	V
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	I _D	A
Pulsed Drain Current ^a			40	
Linear Derating Factor			1.0	W/°C
Single Pulse Avalanche Energy ^b		E _{AS}	630	mJ
Repetitive Avalanche Current ^c		I _{AR}	10	A
Repetitive Avalanche Energy ^c		E _{AR}	12.5	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	125	W
Peak Diode Recovery dV/dt ^c		dV/dt	5.9	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6-32 or M3 screw		10 1.1	lbf · in N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 12.6 mH, R_G = 25 Ω I_{AS} = 10 A (see fig. 12).

c. I_{SD} ≤ 10 A, dV/dt ≤ 330 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

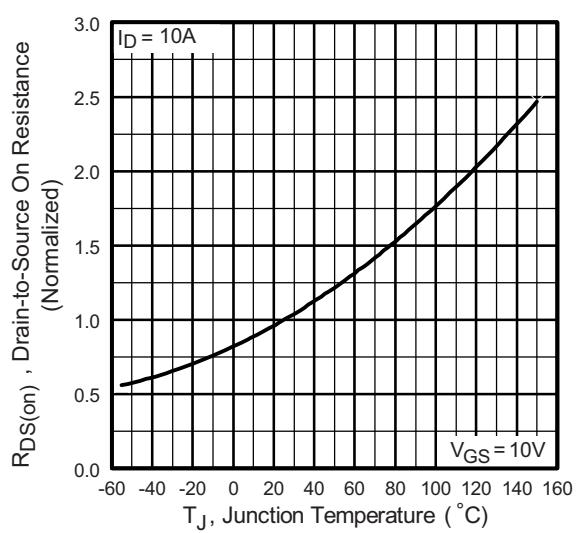
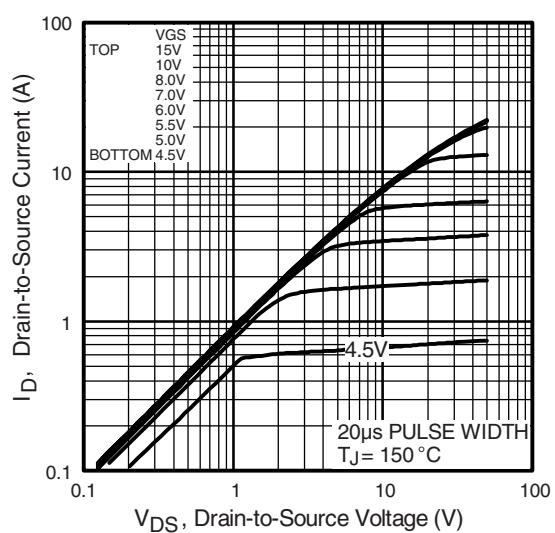
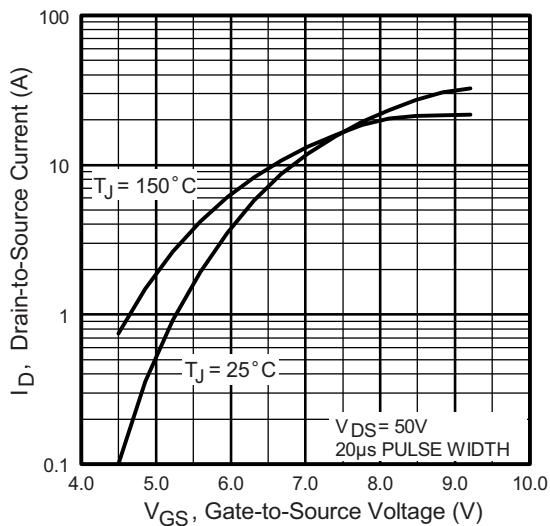
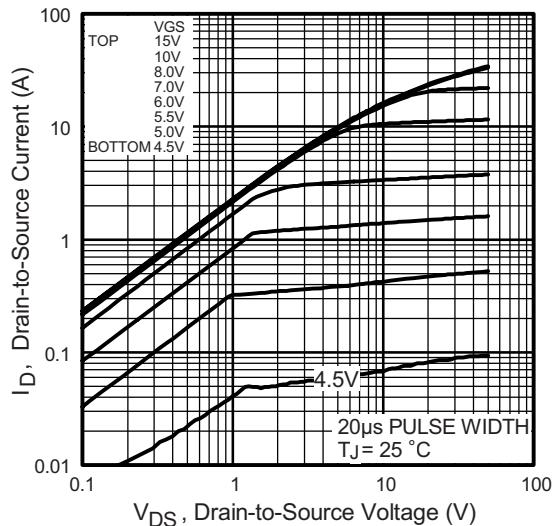
SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	400	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$	-	0.48	-	$\text{V}/{}^{\circ}\text{C}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	-	4.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	25	μA
		$V_{DS} = 320 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 \text{ }^{\circ}\text{C}$	-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 6.0 \text{ A}^b$	-	-	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$	$I_D = 6.0 \text{ A}^b$	4.9	-	-
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}$, see fig. 5	-	1030	-	pF
Output Capacitance	C_{oss}		-	170	-	
Reverse Transfer Capacitance	C_{rss}		-	7.7	-	
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 1.0 \text{ V}, f = 1.0 \text{ MHz}$	-	1490	-	
		$V_{GS} = 0 \text{ V}, V_{DS} = 320 \text{ V}, f = 1.0 \text{ MHz}$	-	52	-	
Effective Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ V to } 320 \text{ V}$	-	61	-	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 10 \text{ A}, V_{DS} = 320 \text{ V},$ see fig. 6 and 13 ^b	-	-	36
Gate-Source Charge	Q_{gs}			-	-	9.9
Gate-Drain Charge	Q_{gd}			-	-	16
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 200 \text{ V}, I_D = 10 \text{ A},$ $R_G = 10 \Omega, R_D = 19.5 \Omega$, see fig. 10 ^b	$I_D = 10 \text{ A}, V_{DS} = 320 \text{ V},$ see fig. 6 and 13 ^b	-	10	-
Rise Time	t_r			-	35	-
Turn-Off Delay Time	$t_{d(off)}$			-	24	-
Fall Time	t_f			-	22	-
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	10
Pulsed Diode Forward Current ^a	I_{SM}			-	-	40
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}, I_S = 10 \text{ A}, V_{GS} = 0 \text{ V}^b$	-	-	2.0	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}, I_F = 10 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	240	360
Body Diode Reverse Recovery Charge	Q_{rr}			-	1.9	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \text{ }\mu\text{s}$; duty cycle $\leq 2 \%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


IRF740A, SiHF740A



Vishay Siliconix

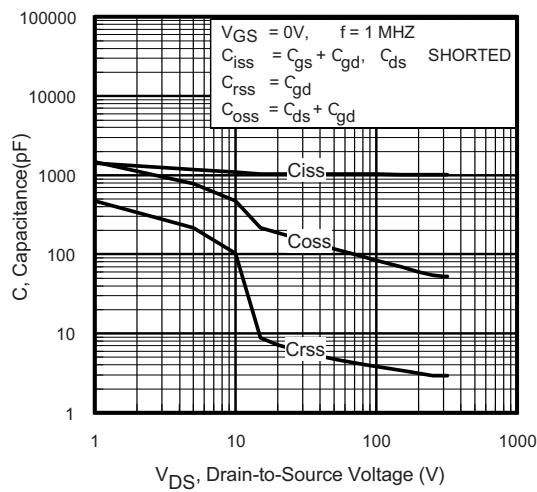


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

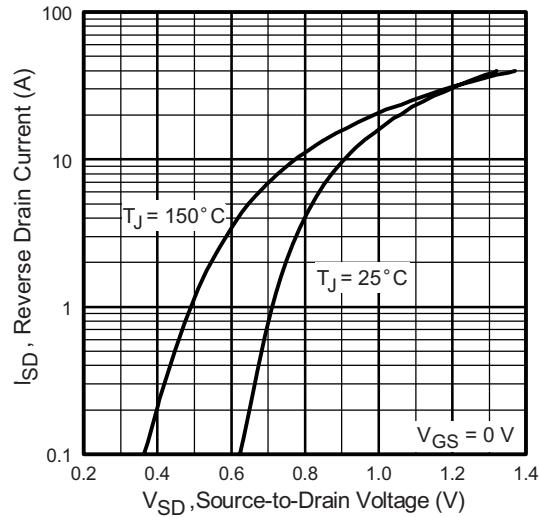


Fig. 7 - Typical Source-Drain Diode Forward Voltage

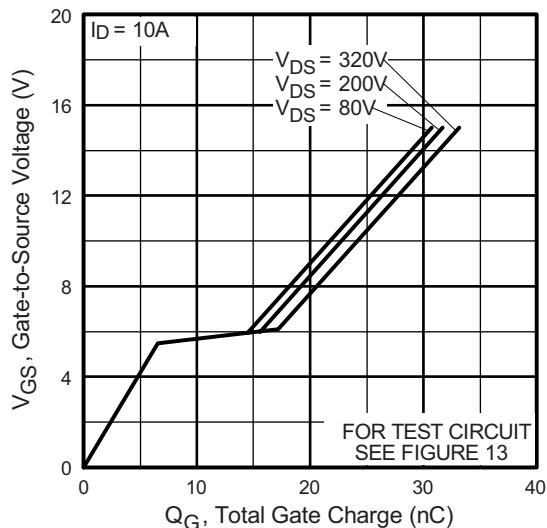


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

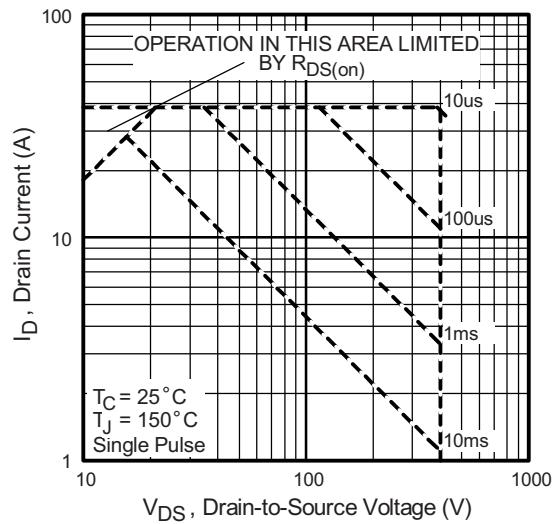


Fig. 8 - Maximum Safe Operating Area

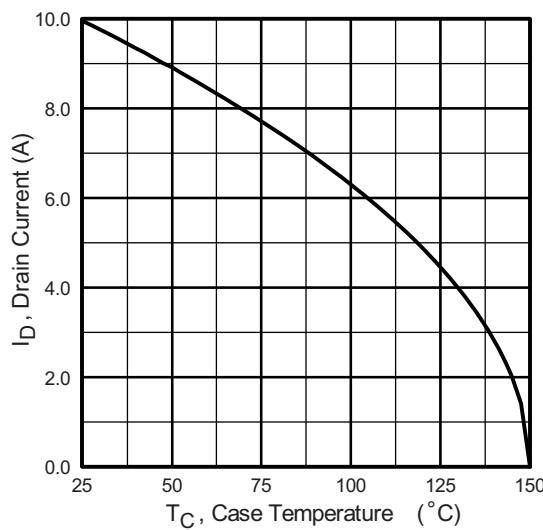


Fig. 9 - Maximum Drain Current vs. Case Temperature

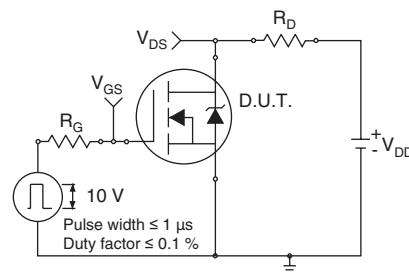


Fig. 10a - Switching Time Test Circuit

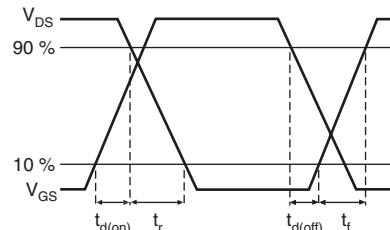


Fig. 10b - Switching Time Waveforms

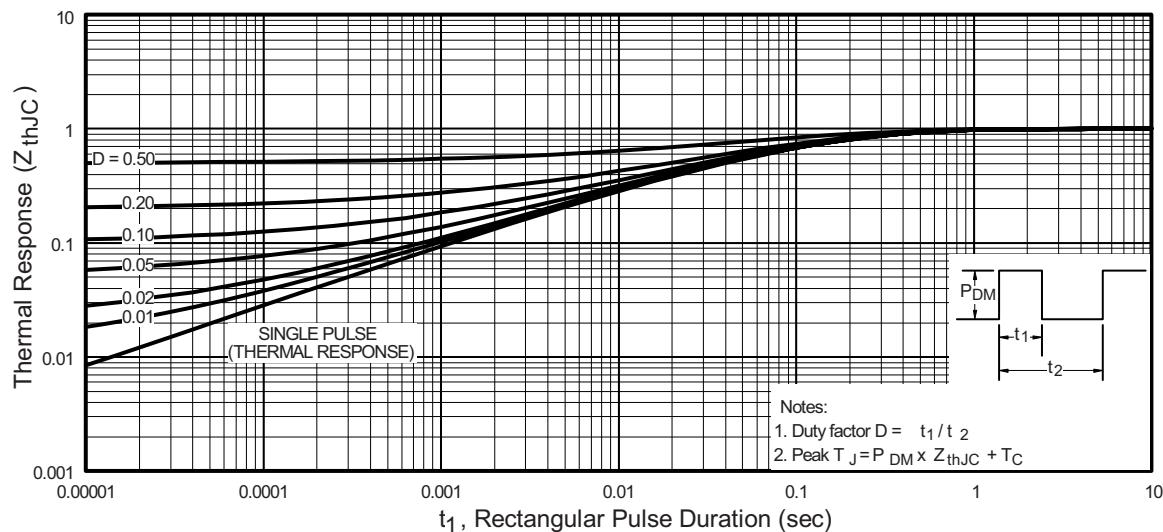


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

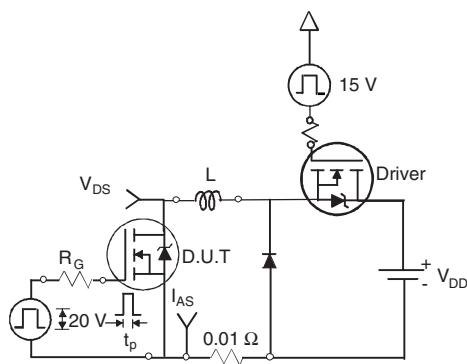


Fig. 12a - Unclamped Inductive Test Circuit

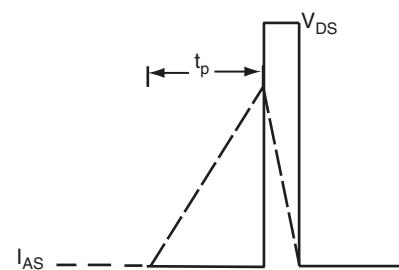


Fig. 12b - Unclamped Inductive Waveforms

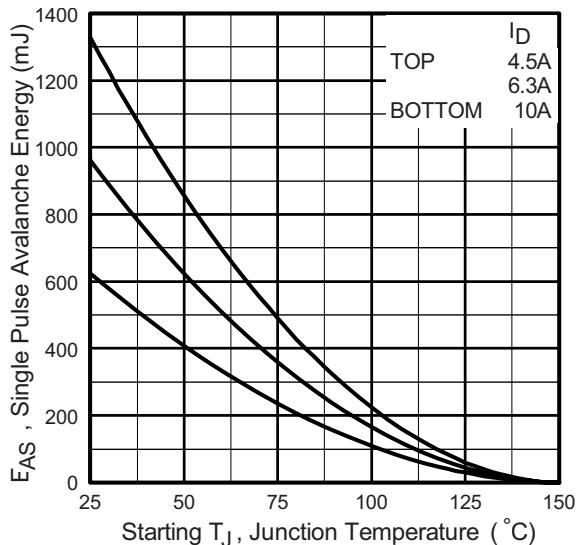


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

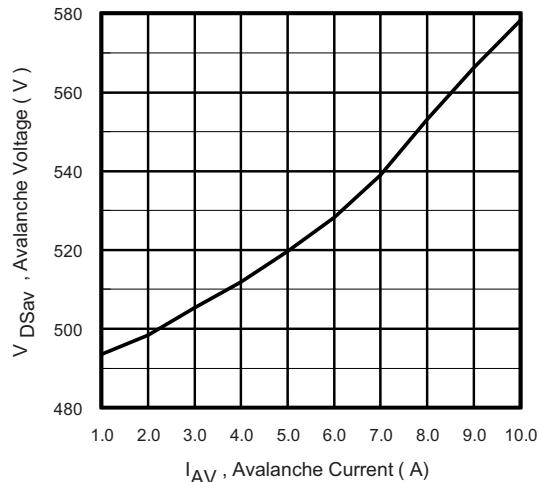


Fig. 12d - Typical Drain-to-Source Voltage Vs. Avalanche Current

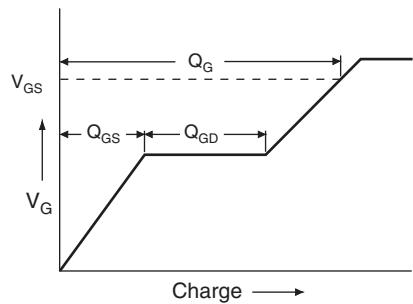


Fig. 13a - Basic Gate Charge Waveform

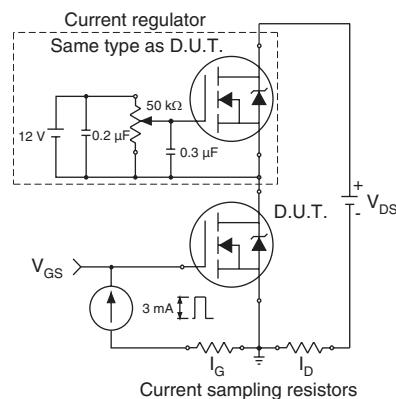
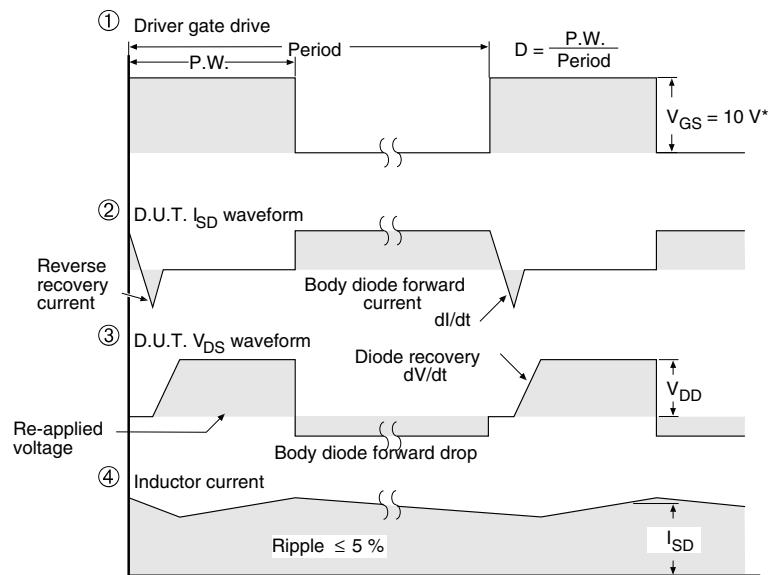
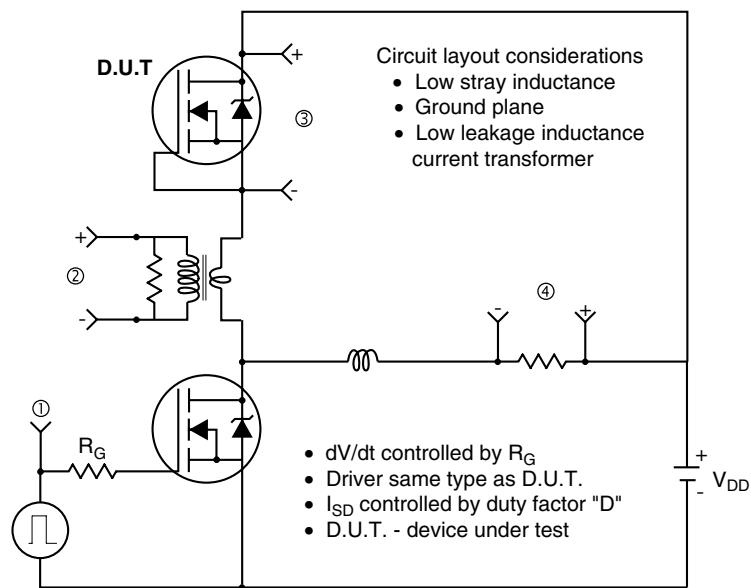


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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